# **Programmable Timer**

The MC14536B programmable timer is a 24–stage binary ripple counter with 16 stages selectable by a binary code. Provisions for an on–chip RC oscillator or an external clock are provided. An on–chip monostable circuit incorporating a pulse–type output has been included. By selecting the appropriate counter stage in conjunction with the appropriate input clock frequency, a variety of timing can be achieved.

- 24 Flip–Flop Stages Will Count From 2<sup>0</sup> to 2<sup>24</sup>
- Last 16 Stages Selectable By Four-Bit Select Code
- 8-Bypass Input Allows Bypassing of First Eight Stages
- Set and Reset Inputs
- Clock Inhibit and Oscillator Inhibit Inputs
- On–Chip RC Oscillator Provisions
- On-Chip Monostable Output Provisions
- Clock Conditioning Circuit Permits Operation With Very Long Rise and Fall Times
- Test Mode Allows Fast Test Sequence
- Supply Voltage Range = 3.0 Vdc to 18 Vdc
- Capable of Driving Two Low–power TTL Loads or One Low–power Schottky TTL Load Over the Rated Temperature Range

# $\label{eq:maximum ratings} \textbf{MAXIMUM RATINGS}^{*} \ (\text{Voltages Referenced to V}_{SS})$

Symbol	Parameter	Value	Unit
V <sub>DD</sub>	DC Supply Voltage	- 0.5 to + 18.0	V
V <sub>in</sub> , V <sub>out</sub>	Input or Output Voltage (DC or Transient)	$-0.5$ to V_DD + 0.5	V
I <sub>in</sub> , I <sub>out</sub>	Input or Output Current (DC or Transient), per Pin	± 10	mA
PD	Power Dissipation, per Package†	500	mW
T <sub>stg</sub>	Storage Temperature	– 65 to + 150	°C
ΤL	Lead Temperature (8–Second Soldering)	260	°C

\* Maximum Ratings are those values beyond which damage to the device may occur. †Temperature Derating:

Plastic "P and D/DW" Packages: - 7.0 mW/°C From 65°C To 125°C Ceramic "L" Packages: - 12 mW/°C From 100°C To 125°C





MC14536B

 $T_A = -55^\circ$  to  $125^\circ$ C for all packages.

## ELECTRICAL CHARACTERISTICS (Voltages Referenced to VSS)

			– 55°C			25°C			125°C	
Characteristic	Symbol	Vdc	Min	Max	Min	Typ #	Max	Min	Max	Unit
Output Voltage "0" Level V <sub>in</sub> = V <sub>DD</sub> or 0	VOL	5.0 10 15		0.05 0.05 0.05		0 0 0	0.05 0.05 0.05		0.05 0.05 0.05	Vdc
"1" Level V <sub>in</sub> = 0 or V <sub>DD</sub>	VOH	5.0 10 15	4.95 9.95 14.95		4.95 9.95 14.95	5.0 10 15		4.95 9.95 14.95		Vdc
$\label{eq:VO} \begin{array}{ll} \mbox{Input Voltage} & "0" \mbox{ Level} \\ \mbox{(V}_{O} = 4.5 \mbox{ or } 0.5 \mbox{ Vdc}) \\ \mbox{(V}_{O} = 9.0 \mbox{ or } 1.0 \mbox{ Vdc}) \\ \mbox{(V}_{O} = 13.5 \mbox{ or } 1.5 \mbox{ Vdc}) \end{array}$	VIL	5.0 10 15		1.5 3.0 4.0		2.25 4.50 6.75	1.5 3.0 4.0		1.5 3.0 4.0	Vdc
"1" Level (V <sub>O</sub> = 0.5 or 4.5 Vdc) (V <sub>O</sub> = 1.0 or 9.0 Vdc) (V <sub>O</sub> = 1.5 or 13.5 Vdc)	VIH	5.0 10 15	3.5 7.0 11		3.5 7.0 11	2.75 5.50 8.25		3.5 7.0 11		Vdc
$\label{eq:constraint} \begin{array}{llllllllllllllllllllllllllllllllllll$	ЮН	5.0 5.0 10 15	- 1.2 - 0.25 - 0.62 - 1.8		- 1.0 - 0.25 - 0.5 - 1.5	- 1.7 - 0.36 - 0.9 - 3.5		- 0.7 - 0.14 - 0.35 - 1.1		mAdc
$\begin{array}{ll} (V_{OH} = 2.5 \ Vdc) & Source \\ (V_{OH} = 4.6 \ Vdc) & Pin \ 13 \\ (V_{OH} = 9.5 \ Vdc) \\ (V_{OH} = 13.5 \ Vdc) \end{array}$		5.0 5.0 10 15	- 3.0 - 0.64 - 1.6 - 4.2		- 2.4 - 0.51 - 1.3 - 3.4	- 4.2 - 0.88 - 2.25 - 8.8	 	- 1.7 - 0.36 - 0.9 - 2.4	 	mAdc
	lol	5.0 10 15	0.64 1.6 4.2		0.51 1.3 3.4	0.88 2.25 8.8		0.36 0.9 2.4		mAdc
Input Current	l <sub>in</sub>	15	—	±0.1	—	±0.00001	±0.1	—	±1.0	μAdc
Input Capacitance (V <sub>in</sub> = 0)	C <sub>in</sub>	_	—	_	—	5.0	7.5	—	_	pF
Quiescent Current (Per Package)	IDD	5.0 10 15		5.0 10 20		0.010 0.020 0.030	5.0 10 20		150 300 600	μAdc
Total Supply Current**† (Dynamic plus Quiescent, Per Package) (C <sub>L</sub> = 50 pF on all outputs, all buffers switching)	ГТ	5.0 10 15			I <sub>T</sub> = (1 I <sub>T</sub> = (2 I <sub>T</sub> = (3	.50 μA/kHz) .30 μA/kHz) .55 μA/kHz)	f + I <sub>DD</sub> f + I <sub>DD</sub> f + I <sub>DD</sub>			μAdc

#Data labelled "Typ" is not to be used for design purposes but is intended as an indication of the IC's potential performance.

\*\* The formulas given are for the typical characteristics only at 25  $^\circ\text{C}.$ 

†To calculate total supply current at loads other than 50 pF:

 $I_T(C_L) = I_T(50 \text{ pF}) + (C_L - 50) \text{ Vfk}$ 

where: IT is in  $\mu$ A (per package), CL in pF, V = (V<sub>DD</sub> - V<sub>SS</sub>) in volts, f in kHz is input frequency, and k = 0.003.

iever (e.g., enner	135 0	•DD): •

MOTOROLA CMOS LOGIC DATA

SWITCHING CHARACTERISTICS*	$(C_L = 50 \text{ pF}, T_A = 25^{\circ}C)$

Characteristic	Symbol	V <sub>DD</sub>	Min	Тур #	Мах	Unit
Output Rise and Fall Time (Pin 13) t <sub>TLH</sub> , t <sub>THL</sub> = (1.5 ns/pF) C <sub>L</sub> + 25 ns t <sub>TLH</sub> , t <sub>THL</sub> = (0.75 ns/pF) C <sub>L</sub> + 12.5 ns t <sub>TLH</sub> , t <sub>THL</sub> = (0.55 ns/pF) C <sub>L</sub> + 9.5 ns	ttlh, tthl	5.0 10 15		100 50 40	200 100 80	ns
Propagation Delay Time Clock to Q1, 8–Bypass (Pin 6) High $t_{PLH}$ , $t_{PHL} = (1.7 \text{ ns/pF}) C_L + 1715 \text{ ns}$ $t_{PLH}$ , $t_{PHL} = (0.66 \text{ ns/pF}) C_L + 617 \text{ ns}$ $t_{PLH}$ , $t_{PHL} = (0.5 \text{ ns/pF}) C_L + 425 \text{ ns}$	<sup>t</sup> PLH, <sup>t</sup> PHL	5.0 10 15	  	1800 650 450	3600 1300 1000	ns
Clock to Q1, 8–Bypass (Pin 6) Low tpLH, tpHL = (1.7 ns/pF) CL + 3715 ns tpLH, tpHL = (0.66 ns/pF) CL + 1467 ns tpLH, tpHL = (0.5 ns/pF) CL + 1075 ns	<sup>t</sup> PLH, <sup>t</sup> PHL	5.0 10 15	 	3.8 1.5 1.1	7.6 3.0 2.3	μs
Clock to Q16 tpHL, tpLH = (1.7 ns/pF) CL + 6915 ns tpHL, tpLH = (0.66 ns/pF) CL + 2967 ns tpHL, tpLH = (0.5 ns/pF) CL + 2175 ns	<sup>t</sup> PLH, <sup>t</sup> PHL	5.0 10 15		7.0 3.0 2.2	14 6.0 4.5	μs
Reset to Q <sub>n</sub> t <sub>PHL</sub> = (1.7 ns/pF) C <sub>L</sub> + 1415 ns t <sub>PHL</sub> = (0.66 ns/pF) C <sub>L</sub> + 567 ns t <sub>PHL</sub> = (0.5 ns/pF) C <sub>L</sub> + 425 ns	<sup>t</sup> PHL	5.0 10 15		1500 600 450	3000 1200 900	ns
Clock Pulse Width	tWH	5.0 10 15	600 200 170	300 100 85		ns
Clock Pulse Frequency (50% Duty Cycle)	f <sub>cl</sub>	5.0 10 15		1.2 3.0 5.0	0.4 1.5 2.0	MHz
Clock Rise and Fall Time	tтLH, tтнL	5.0 10 15		No Limit		—
Reset Pulse Width	tWH	5.0 10 15	1000 400 300	500 200 150		ns

\* The formulas given are for the typical characteristics only at 25°C.

#Data labelled "Typ" is not to be used for design purposes but is intended as an indication of the IC's potential performance.

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation,  $V_{in}$  and  $V_{out}$  should be constrained to the range  $V_{SS} \leq (V_{in} \text{ or } V_{out}) \leq V_{DD}$ . Unused inputs must always be tied to an appropriate logic voltage level (e.g., either  $V_{SS}$  or  $V_{DD}$ ). Unused outputs must be left open.

# **PIN ASSIGNMENT**

			_
SET [	1•	16	] ∨ <sub>DD</sub>
RESET	2	15	] моло іл
IN 1 [	3	14	] OSC INH
OUT 1 [	4	13	] DECODE
OUT 2 [	5	12	]D
8-BYPASS	6	11	] C
CLOCK INH	7	10	]в
v <sub>ss</sub> [	8	9	A

## INPUTS

**SET (Pin 1)** — A high on Set asynchronously forces Decode Out to a high level. This is accomplished by setting an output conditioning latch to a high level while at the same time resetting the 24 flip–flop stages. After Set goes low (inactive), the occurrence of the first negative clock transition on IN<sub>1</sub> causes Decode Out to go low. The counter's flip–flop stages begin counting on the second negative clock transition of IN<sub>1</sub>. When Set is high, the on–chip RC oscillator is disabled. This allows for very low–power standby operation.

**RESET (Pin 2)** — A high on Reset asynchronously forces Decode Out to a low level; all 24 flip–flop stages are also reset to a low level. Like the Set input, Reset disables the on–chip RC oscillator for standby operation.

**IN<sub>1</sub> (Pin 3)** — The device's internal counters advance on the negative–going edge of this input. IN<sub>1</sub> may be used as an external clock input or used in conjunction with  $OUT_1$  and  $OUT_2$  to form an RC oscillator. When an external clock is used, both  $OUT_1$  and  $OUT_2$  may be left unconnected or used to drive 1 LSTTL or several CMOS loads.

**8–BYPASS (Pin 6)** — A high on this input causes the first 8 flip–flop stages to be bypassed. This device essentially becomes a 16–stage counter with all 16 stages selectable. Selection is accomplished by the A, B, C, and D inputs. (See the truth tables.)

**CLOCK INHIBIT (Pin 7)** — A high on this input disconnects the first counter stage from the clocking source. This holds the present count and inhibits further counting. However, the clocking source may continue to run. Therefore, when Clock Inhibit is brought low, no oscillator start–up time is required. When Clock Inhibit is low, the counter will start counting on the occurrence of the first negative edge of the clocking source at IN<sub>1</sub>.

**OSC INHIBIT (Pin 14)** — A high level on this pin stops the RC oscillator which allows for very low–power standby operation. May also be used, in conjunction with an external clock, with essentially the same results as the Clock Inhibit input.

**MONO–IN (Pin 15)** — Used as the timing pin for the onchip monostable multivibrator. If the Mono–In input is connected to V<sub>SS</sub>, the monostable circuit is disabled, and Decode Out is directly connected to the selected Q output. The monostable circuit is enabled if a resistor is connected between Mono–In and V<sub>DD</sub>. This resistor and the device's internal capacitance will determine the minimum output pulse widths. With the addition of an external capacitor to V<sub>SS</sub>, the pulse width range may be extended. For reliable operation the resistor value should be limited to the range of 5 k $\Omega$  to 100 k $\Omega$  and the capacitor value should be limited to a maximum of 1000 pf. (See figures 3, 4, 5, and 10).

A, B, C, D (Pins 9, 10, 11, 12) — These inputs select the flip–flop stage to be connected to Decode Out. (See the truth tables.)

## OUTPUTS

 $OUT_1$ ,  $OUT_2$  (Pin 4, 5) — Outputs used in conjunction with IN<sub>1</sub> to form an RC oscillator. These outputs are buffered and may be used for 2<sup>0</sup> frequency division of an external clock.

**DECODE OUT (Pin 13)** — Output function depends on configuration. When the monostable circuit is disabled, this output is a 50% duty cycle square wave during free run.

### TEST MODE

The test mode configuration divides the 24 flip–flop stages into three 8–stage sections to facilitate a fast test sequence. The test mode is enabled when 8–Bypass, Set and Reset are at a high level. (See Figure 8.)

# TRUTH TABLES

	Stage Selected				
8–Bypass	D	С	В	Α	for Decode Out
0	0	0	0	0	9
0	0	0	0	1	10
0	0	0	1	0	11
0	0	0	1	1	12
0	0	1	0	0	13
0	0	1	0	1	14
0	0	1	1	0	15
0	0	1	1	1	16
0	1	0	0	0	17
0	1	0	0	1	18
0	1	0	1	0	19
0	1	0	1	1	20
0	1	1	0	0	21
0	1	1	0	1	22
0	1	1	1	0	23
0	1	1	1	1	24

	Stage Selected				
8–Bypass	D	С	В	Α	for Decode Out
1	0	0	0	0	1
1	0	0	0	1	2
1	0	0	1	0	3
1	0	0	1	1	4
1	0	1	0	0	5
1	0	1	0	1	6
1	0	1	1	0	7
1	0	1	1	1	8
1	1	0	0	0	9
1	1	0	0	1	10
1	1	0	1	0	11
1	1	0	1	1	12
1	1	1	0	0	13
1	1	1	0	1	14
1	1	1	1	0	15
1	1	1	1	1	16

# FUNCTION TABLE

In <sub>1</sub>	Set	Reset	Clock Inh	OSC Inh	Out 1	Out 2	Decode Out
~	0	0	0	0	<u>`</u>	~	No Change
~	0	0	0	0	~	~	Advance to next state
Х	1	0	0	0	0	1	1
Х	0	1	0	0	0	1	0
Х	0	0	1	0	—	_	No Change
Х	0	0	0	1	0	1	No Change
0	0	0	0	Х	0	1	No Change
1	0	0	0	٦.	~	7	Advance to next state

X = Don't Care

LOGIC DIAGRAM







100

Figure 4. Typical Cx versus Pulse Width @ V<sub>DD</sub> = 10 V

CX, EXTERNAL CAPACITANCE (pF)

100

100 kΩ  $R_{\chi} =$ 

1.0

0.1

1.0

T<sub>A</sub> = 25°C

 $V_{DD} = 5 V$ 

1000

50 kΩ

10 kΩ

5kΩ

10



 $R\chi = 100 k\Omega$ 

1.0

0.1

1.0

50 kΩ

10 kΩ  $5 \text{ k}\Omega$  T

10

T<sub>A</sub> = 25°C

V<sub>DD</sub> = 10 V-

1000

VDD .0.01 μF 500 μF In SET RESET OUT 8-BYPASS o Т PULSE  $IN_1$ o GENERATOR C INH o MONO IN OUT OSC INH PULSE  $\sim$ Δ GENERATOR В a С DECODE o OUT D ۶<sub>vss</sub> A В С = 20 ns 20 ns D 90 50% 10% 50% DUTY CYCLE



Figure 7. Switching Time Test Circuit and Waveforms



# FUNCTIONAL TEST SEQUENCE

Test function (Figure 8) has been included for the reduction of test time required to exercise all 24 counter stages. This test function divides the counter into three 8–stage sections and 255 counts are loaded in each of the 8–stage sections in parallel. All flip–flops are now at a "1". The counter is now returned to the normal 24–stages in series configuration. One more pulse is entered into  $ln_1$  which will cause the counter to ripple from an all "1" state to an all "0" state.



Figure 8. Functional Test Circuit

# FUNCTIONAL TEST SEQUENCE

	In	puts		Outputs	Comments
In <sub>1</sub>	Set	Reset	8–Bypass	Decade Out Q1 thru Q24	All 24 stages are in Reset mode.
1	0	1	1	0	
1	1	1	1	0	Counter is in three 8 stage sections in parallel mode.
0	1	1	1	0	First "1" to "0" transition of clock.
1 0 	1	1	1		255 "1" to "0" transitions are clocked in the counter.
0	1	1	1	1	The 255 "1" to "0" transition.
0	0	0	0	1	Counter converted back to 24 stages in series mode. Set and Reset must be connected together and simultaneously go from "1" to "0".
1	0	0	0	1	In <sub>1</sub> Switches to a "1".
0	0	0	0	0	Counter Ripples from an all "1" state to an all "0" state.



NOTE: When power is first applied to the device, Decode Out can be either at a high or low state. On the rising edge of a Set pulse the output goes high if initially at a low state. The output remains high if initially at a high state. Because Clock Inh is held high, the clock source on the input pin has no effect on the output. Once Clock Inh is taken low, the output goes low on the first negative clock transition. The output returns high depending on the 8–Bypass, A, B, C, and D inputs, and the clock input period. A 2<sup>n</sup> frequency division (where n = the number of stages selected from the truth table) is obtainable at Decode Out. A 2<sup>0</sup>–divided output of IN<sub>1</sub> can be obtained at OUT<sub>1</sub> and OUT<sub>2</sub>.

Figure 9. Time Interval Configuration Using an External Clock, Set, and Clock Inhibit Functions (Divide-by-2 Configured)



NOTE: When Power is first applied to the device with the Reset input going high, Decode Out initializes low. Bringing the Reset input low enables the chip's internal counters. After Reset goes low, the 2<sup>n</sup>/2 negative transition of the clock input causes Decode Out to go high. Since the Mono–In input is being used, the output becomes monostable. The pulse width of the output is dependent on the external timing components. The second and all subsequent pulses occur at 2<sup>n</sup> x (the clock period) intervals where n = the number of stages selected from the truth table.

#### Figure 10. Time Interval Configuration Using an External Clock, Reset, and Output Monostable to Achieve a Pulse Output (Divide-by-4 Configured)



NOTE: This circuit is designed to use the on-chip oscillation function. The oscillator frequency is determined by the external R and C components. When power is first applied to the device, Decode Out initializes to a high state. Because this output is tied directly to the Osc-Inh input, the oscillator is disabled. This puts the device in a low-current standby condition. The rising edge of the Reset pulse will cause the output to go low. This in turn causes Osc-Inh to go low. However, while Reset is high, the oscillator is still disabled (i.e.: standy condition). After Reset goes low, the output remains low for 2<sup>n</sup>/2 of the oscillator's period. After the part times out, the output again goes high.

#### Figure 11. Time Interval Configuration Using On–Chip RC Oscillator and Reset Input to Initiate Time Interval (Divide–by–2 Configured)

## **OUTLINE DIMENSIONS**



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